

CY14B101KA CY14B101MA

1-Mbit (128 K × 8/64 K × 16) nvSRAM with Real Time Clock

Features

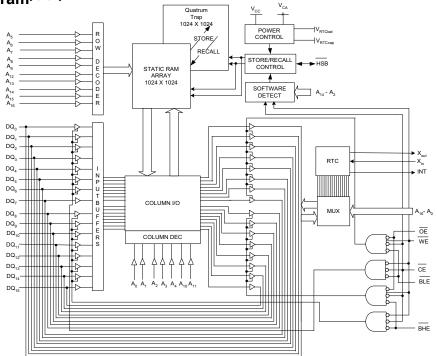
- 1-Mbit nonvolatile static random access memory (nvSRAM)
 - 25 ns and 45 ns access times
 - □ Internally organized as 128 K × 8 (CY14B101KA) or 64 K × 16 (CY14B101MA)
 - Hands off automatic STORE on power-down with only a small capacitor
 - STORE to QuantumTrap nonvolatile elements is initiated by software, hardware, or AutoStore on power-down
 - RECALL to SRAM initiated on power-up or by software
- High reliability
 - □ Infinite Read, Write, and RECALL cycles
 - I million STORE cycles to QuantumTrap
 - 20 year data retention
- Real time clock (RTC)
 - Full featured real time clock
 - Watchdog timer
 - Clock alarm with programmable interrupts
 - Capacitor or battery backup for RTC
 - □ Backup current of 0.35 µA (Typ)

- Industry standard configurations
 Single 3 V +20%, -10% operation
 Industrial temperature
- Packages
 - □ 44-/54-pin thin small outline package (TSOP) Type II □ 48-pin shrink small outline package (SSOP)
- Pb-free and restriction of hazardous substances (RoHS) compliant

Functional Description

The Cypress CY14B101KA/CY14B101MA combines a 1-Mbit nvSRAM with a full featured real time clock in a monolithic integrated circuit. The embedded nonvolatile elements incorporate QuantumTrap technology producing the world's most reliable nonvolatile memory. The SRAM is read and written an infinite number of times, while independent nonvolatile data resides in the nonvolatile elements.

The real time clock function provides an accurate clock with leap year tracking and a programmable, high accuracy oscillator. The alarm function is programmable for periodic minutes, hours, days, or months alarms. There is also a programmable watchdog timer for process control.



Notes

- 1. Address A_0-A_{16} for × 8 configuration and Address A_0-A_{15} for × 16 configuration.
- 2. <u>Data</u> $DQ_0 DQ_7$ for × 8 configuration and Data $DQ_0 DQ_{15}$ for × 16 configuration.

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3. BHE and BLE are applicable for × 16 configuration only.

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Logic Block Diagram^[1, 2, 3]



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Pinouts

Figure 1. Pin Diagram – 44-pin, 54-pin TSOP II, and 48-pin SSOP

$ \begin{array}{c c c c c c c c c c c c c c c c c c c $	44 HSB 43 NC[6] 42 NC[5] 41 NC[4] 40 NC 39 A ₁₆ 38 A ₁₅ 37 OE 36 DQ ₇ 35 DQ ₆ 34 V _{SS} 33 V _{CC} 32 DQ5 31 DQ4 30 V _{CAP} 29 A ₁₄ 28 A ₁₃ 27 A ₁₂ 26 A ₁₁ 25 A ₁₀ 24 V _{RTCcap} 23 V _{RTCcat}	$\begin{array}{c} V_{CAP} \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \ \$	48-pin SSOP (× 8) Top View (not to scale)	48 VCC 47 A ₁₅ 46 HSB 45 WE 44 A ₁₃ 43 A ₈ 42 A ₉ 41 NC 40 A ₁₁ 39 NC 38 NC 37 NC 36 VSS 35 VC 34 VRTCcap 33 DQ6 32 OE 31 A ₁₀ 30 CE 29 DQ7 28 DQ5 27 DQ4 26 DQ3 25 VCC	$\begin{array}{c ccccccccccccccccccccccccccccccccccc$	44 DQ ₁₃ 43 DQ ₁₂ 42 V _{SS}
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Notes

- Address expansion for 2-Mbit. NC pin not connected to die.
 Address expansion for 4-Mbit. NC pin not connected to die.
 Address expansion for 8-Mbit. NC pin not connected to die.
 Address expansion for 16-Mbit. NC pin not connected to die.



Pin Definitions

Pin Name	I/O Type	Description
A ₀ -A ₁₆	Input	Address inputs. Used to select one of the 131,072 Bytes of the nvSRAM for × 8 configuration.
A ₀ -A ₁₅	input	Address inputs. Used to select one of the 65,536 Words of the nvSRAM for × 16 configuration.
DQ ₀ -DQ ₇	Input/Output	Bidirectional data I/O Lines for × 8 configuration. Used as input or output lines depending on operation.
DQ ₀ -DQ ₁₅	input/Output	Bidirectional data I/O Lines for × 16 configuration. Used as input or output lines depending on operation.
NC	No connect	No connects. This pin is not connected to the die.
WE	Input	Write Enable input, Active LOW. When the chip is enabled and $\overline{\text{WE}}$ is LOW, data on the I/O pins is written to the specific address location.
CE	Input	Chip Enable input, Active LOW. When LOW, selects the chip. When HIGH, deselects the chip.
ŌĒ	Input	Output Enable, Active LOW. The active LOW OE input enables the data output buffers during read cycles. Deasserting OE HIGH causes the I/O pins to tristate.
BHE	Input	Byte High Enable, Active LOW. Controls DQ ₁₅ –DQ ₈ .
BLE	Input	Byte Low Enable, Active LOW. Controls DQ7–DQ0.
X _{out}	Output	Crystal connection. Drives crystal on start up.
X _{in}	Input	Crystal connection. For 32.768 kHz crystal.
V _{RTCcap}	Power supply	Capacitor supplied backup RTC supply voltage. Left unconnected if V _{RTCbat} is used.
V _{RTCbat}	Power supply	Battery supplied backup RTC supply voltage. Left unconnected if V _{RTCcap} is used.
INT	Output	Interrupt output. Programmable to respond to the clock alarm, the watchdog timer, and the power monitor. Also programmable to either active HIGH (push or pull) or LOW (open drain).
V _{SS}	Ground	Ground for the device. Must be connected to the ground of the system.
V _{CC}	Power supply	Power supply inputs to the device. 3.0 V +20%, -10%
HSB	Input/Output	Hardware STORE Busy (HSB). When LOW this output indicates that a Hardware STORE is in progress. When pulled LOW external to the <u>chip</u> it initiates a nonvolatile STORE operation. After each Hardware and Software STORE operation HSB is driven HIGH for short time (t _{HHHD}) with standard output high current and then weak internal pull-up resistor keeps this pin HIGH (External pull-up resistor connection optional).
V _{CAP}	Power supply	AutoStore capacitor. Supplies power to the nvSRAM during power loss to store data from SRAM to nonvolatile elements.



Device Operation

The CY14B101KA/CY14B101MA nvSRAM is made up of two functional components paired in the same physical cell. These are a SRAM memory cell and a nonvolatile QuantumTrap cell. The SRAM memory cell operates as a standard fast static RAM. Data in the SRAM is transferred to the nonvolatile cell (the STORE operation), or from the nonvolatile cell to the SRAM (the RECALL operation). Using this unique architecture, all cells are stored and recalled in parallel. During the STORE and RECALL operations SRAM read and write operations are inhibited. The CY14B101KA/CY14B101MA supports infinite reads and writes similar to a typical SRAM. In addition, it provides infinite RECALL operations. Refer Truth Table For SRAM Operations on page 26 for a complete description of read and write modes.

SRAM Read

The CY14B101KA/CY14B101MA performs a read cycle whenever CE and OE are LOW, and WE and HSB are HIGH. The address specified on pins A_{0-16} or A_{0-15} determines which of the 131,072 data bytes or 65,536 words of 16 bits each are accessed. Byte enables (BHE, BLE) determine which bytes are enabled to the output, in the case of 16-bit words. When the read is initiated by an address transition, the outputs are valid after a delay of t_{AA} (read cycle #1). If the read is initiated by CE or OE, the outputs are valid at t_{ACE} or at t_{DOE} , whichever is later (read cycle #2). The data output repeatedly responds to address changes within the t_{AA} access time without the need for transitions on any control input pins. This remains valid until another address change or until CE or OE is brought HIGH, or WE or HSB is brought LOW.

SRAM Write

A write cycle is performed when \overline{CE} and \overline{WE} are LOW and \overline{HSB} is HIGH. The address inputs must be stable before entering the write cycle and must remain stable until \overline{CE} or \overline{WE} goes HIGH at the end of the cycle. The data on the common I/O pins IO_{0-7} are written into the memory if it is valid t_{SD} before the end of a WE-controlled write, or before the end of an CE-controlled write. The Byte Enable inputs (BHE, BLE) determine which bytes are written, in the case of 16-bit words. It is recommended that \overline{OE} be kept HIGH during the entire write cycle to avoid data bus contention on common I/O lines. If \overline{OE} is left LOW, internal circuitry turns off the output buffers t_{HZWE} after WE goes LOW.

AutoStore Operation

The CY14B101KA/CY14B101MA stores data to the nvSRAM using one of three storage operations. <u>These</u> three operations are: Hardware STORE, activated by the HSB; Software STORE, activated by an address sequence; AutoStore, on device power-down. The AutoStore operation is a unique feature of QuantumTrap technology and is enabled by default on the CY14B101KA/CY14B101MA.

During a normal operation, the device draws current from V_{CC} to charge a capacitor connected to the V_{CAP} pin. This stored charge is used by the chip to perform a single STORE operation. If the voltage on the V_{CC} pin drops below V_{SWITCH}, the part

automatically disconnects the V_{CAP} pin from $V_{CC}.$ A STORE operation is initiated with power provided by the V_{CAP} capacitor.

Note If the capacitor is not connected to V_{CAP} pin, AutoStore must be disabled using the soft sequence specified in Preventing AutoStore on page 7. In case AutoStore is enabled without a capacitor on V_{CAP} pin, the device attempts an AutoStore operation without sufficient charge to complete the Store. This corrupts the data stored in nvSRAM.

Figure 2. AutoStore Mode

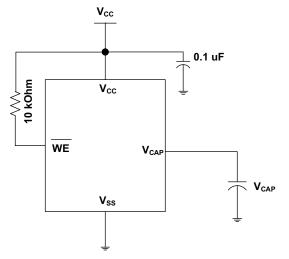


Figure 2 shows the proper connection of the storage capacitor (V_{CAP}) for automatic STORE operation. Refer to DC Electrical Characteristics on page 17 for the size of the V_{CAP} . The voltage on the V_{CAP} pin is driven to V_{CC} by a regulator on the chip. A pull-up should be placed on WE to hold it inactive during power-up. This pull-up is only effective if the WE signal is tristate during power-up. Many MPUs tristate their controls on power-up. This should be verified when using the pull-up. When the nvSRAM comes out of power-on-RECALL, the MPU must be active or the WE held inactive until the MPU comes out of reset.

To reduce unnecessary nonvolatile stores, AutoStore and Hardware STORE operations are ignored unless at least one write operation has taken place since the most recent STORE or RECALL cycle. Software initiated STORE cycles are performed regardless of whether a write operation has taken place.

The HSB signal is monitored by the system to detect if an AutoStore cycle is in progress.

Hardware STORE (HSB) Operation

The CY14B101KA/CY14B101MA provides the $\overline{\text{HSB}}$ pin to control and acknowledge the STORE operations. The <u>HSB</u> pin is used to request a Hardware STORE cycle. When the HSB pin is driven LOW, the CY14B101KA/CY14B101MA conditionally initiates a STORE operation after t_{DELAY}. An actual STORE cycle begins only if a write to the SRAM has taken place since the last STORE or RECALL cycle. The HSB pin also acts as an open drain driver (internal 100 k Ω weak pull-up resistor) that is internally driven LOW to indicate a busy condition when the STORE (initiated by any means) is in progress.

Note After each Hardware and Software STORE operation $\overline{\text{HSB}}$ is driven HIGH for a short time (t_{HHHD}) with standard output high



current and then remains HIGH by internal 100 $\mbox{k}\Omega$ pull-up resistor.

SRAM write operations that are in progress when $\overline{\text{HSB}}$ is driven LOW by any means are given time (t_{DELAY}) to complete before the STORE operation is initiated. However, any SRAM write cycles requested after HSB goes LOW are in<u>hibited</u> until HSB returns HIGH. In case the write latch is not set, HSB is not driven LOW by the CY14B101KA/CY14B101MA. But any SRAM read and write cycles are inhibited until HSB is returned HIGH by MPU or other external source.

During any STORE operation, regardless of how it is <u>initiated</u>, the CY14B101KA/CY14B101MA continues to drive the HSB pin LOW, releasing it only when the STORE is complete. Upon completion of the STORE operation, <u>the</u> nvSRAM memory access is <u>inhibited</u> for t_{LZHSB} time after HSB pin returns HIGH. Leave the HSB unconnected if it is not used.

Hardware RECALL (Power-Up)

During power-up or after any low power condition (V_{CC}
 V_{SWITCH}), an internal RECALL request is latched. When V_{CC} again exceeds the V_{SWITCH} on powerup, a RECALL cycle is automatically initiated and takes $t_{HRECALL}$ to complete. During this time, the HSB pin is driven LOW by the HSB driver and all reads and writes to nvSRAM are inhibited.

Software STORE

Data is transferred from the SRAM to the nonvolatile memory by a software address sequence. The CY14B101KA/CY14B101MA <u>Software STORE cycle is initiated by executing sequential CE or</u> OE controlled read cycles from six specific address locations in exact order. During the STORE cycle, an erase of the previous nonvolatile data is first performed, followed by a program of the nonvolatile elements. After a STORE cycle is initiated, further input and output are disabled until the cycle is completed.

Because a sequence of reads from specific addresses is used for STORE initiation, it is important that no other read or write accesses intervene in the sequence, or the sequence is aborted and no STORE or RECALL takes place.

To initiate the Software STORE cycle, the following read sequence must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x8FC0 Initiate STORE cycle

The software sequence may <u>be clocked with CE</u> controlled reads or OE controlled reads, with WE kept HIGH for all the six READ sequences. After the sixth address in the sequence is entered, the STORE cycle commences and the chip is disabled. HSB is driven LOW. After the t_{STORE} cycle time is fulfilled, the SRAM is activated again for the read and write operation.

Software RECALL

Data is transferred from the nonvolatile memory to the SRAM by a software address sequence. A Software RECALL cycle is initiated with a sequence of read operations in a manner similar to the Software STORE initiation. To initiate the RECALL cycle, the following sequence of CE or OE controlled read operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x4C63 Initiate RECALL cycle

Internally, RECALL is a two step procedure. First, the SRAM data is cleared. Next, the nonvolatile information is transferred into the SRAM cells. After the t_{RECALL} cycle time, the SRAM is again ready for read and write operations. The RECALL operation does not alter the data in the nonvolatile elements.



Table 1. Mode Selection

CE	WE	OE	BHE, BLE ^[8]	A ₁₅ -A ₀ ^[9]	Mode	I/O	Power
Н	X	Х	Х	Х	Not selected	Output high Z	Standby
L	Н	L	L	Х	Read SRAM	Output data	Active
L	L	Х	L	Х	Write SRAM	Input data	Active
L	н	L	X	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8B45	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM AutoStore Disable	Output data Output data Output data Output data Output data Output data	Active ^[10]
L	н	L	Х	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4B46	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM AutoStore Enable	Output data Output data Output data Output data Output data Output data	Active ^[10]
L	н	L	X	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x8FC0	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile STORE	Output data Output data Output data Output data Output data Output high Z	Active I _{CC2} ^[10]
L	н	L	X	0x4E38 0xB1C7 0x83E0 0x7C1F 0x703F 0x4C63	Read SRAM Read SRAM Read SRAM Read SRAM Read SRAM Nonvolatile RECALL	Output data Output data Output data Output data Output data Output high Z	Active ^[10]

Preventing AutoStore

The AutoStore function is disabled by initiating an AutoStore disable sequence. A sequence of read operations is performed in a manner similar to the Software STORE initiation. To initiate the AutoStore disable sequence, the following sequence of CE or OE controlled read operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x8B45 AutoStore Disable

The AutoStore is reenabled by initiating an AutoStore enable sequence. A sequence of read operations is performed in a manner similar to the Software RECALL initiation.

To initiate the AutoStore enable sequence, the following sequence of CE or OE controlled read operations must be performed:

- 1. Read address 0x4E38 Valid READ
- 2. Read address 0xB1C7 Valid READ
- 3. Read address 0x83E0 Valid READ
- 4. Read address 0x7C1F Valid READ
- 5. Read address 0x703F Valid READ
- 6. Read address 0x4B46 AutoStore Enable

If the AutoStore function is disabled or reenabled, a manual STORE operation (Hardware or Software) issued to save the AutoStore state through subsequent power-down cycles. The part comes from the factory with AutoStore enabled.

Notes

8. BHE and BLE are applicable for \times 16 configuration only.

10. The six consecutive address locations must be in the order listed. WE must be HIGH during all six cycles to enable a nonvolatile cycle.

While there are 17 address lines on the CY14B101KA (16 address lines on the CY14B101MA), only the 13 address lines (A₁₄-A₂) are used to control software modes. The remaining address lines are don't care.



Data Protection

The CY14B101KA/CY14B101MA protects data from corruption during low voltage conditions by inhibiting all externally initiated STORE and write operations. The low voltage condition is detected when V_{CC} is less than V_{SWITCH} . If the CY14B101KA/CY14B101MA is in a write mode (both CE and WE are LOW) at power-up, after a RECALL or ST<u>ORE</u>, the write is inhibited until the SRAM is enabled after t_{LZHSB} (HSB to output active). This protects against inadvertent writes during power-up or brown out conditions.

Noise Considerations

Refer to CY application note AN1064.

Real Time Clock Operation

nvTIME Operation

The CY14B101KA/CY14B101MA offers internal registers that contain clock, alarm, watchdog, interrupt, and control functions. RTC registers use the last 16 address locations of the SRAM. Internal double buffering of the clock and timer information registers prevents accessing transitional internal clock data during a read or write operation. Double buffering also circumvents disrupting normal timing counts or the clock acturacy of the internal clock when accessing clock data. Clock and alarm registers store data in BCD format.

RTC functionality is described with respect to CY14B101KA in the following sections. The same description applies to CY14B101MA, except for the RTC register addresses. The RTC register addresses for CY14B101KA range from 0x1FFF0 to 0x1FFFF, while those for CY14B101MA range from 0x0FFF0 to 0x0FFFF. Refer to Table 3 on page 12 and Table 4 on page 13 for a detailed Register Map description.

Clock Operations

The clock registers maintain time up to 9,999 years in one second increments. The time can be set to any calendar time and the clock automatically keeps track of days of the week and month, leap years, and century transitions. There are eight registers dedicated to the clock functions, which are used to set time with a write cycle and to read time during a read cycle. These registers contain the time of day in BCD format. Bits defined as '0' are currently not used and are reserved for future use by Cypress.

Reading the Clock

The double buffered RTC register structure reduces the chance of reading incorrect data from the clock. Stop internal updates to the CY14B101KA time keeping registers before reading clock data, to prevent reading of data in transition. Stopping the register updates does not affect clock accuracy.

The updating process is stopped by writing a '1' to the read bit 'R' (in the flags register at 0x1FFF0), and does not restart until a '0' is written to the read bit. The RTC registers are then read while the internal clock continues to run. After a '0' is written to the read bit ('R'), all RTC registers are simultaneously updated within 20 ms.

Setting the Clock

Setting the write bit 'W' (in the flags register at 0x1FFF0) to a '1' stops updates to the time keeping registers and enables the time to be set. The correct day, date, and time is then written into the registers and must be in 24-hour BCD format. The time written is referred to as the "Base Time". This value is stored in nonvolatile registers and used in the calculation of the current time. Resetting the write bit to '0' transfers the values of timekeeping registers to the actual clock counters, after which the clock resumes normal operation.

If the time written to the timekeeping registers is not in the correct BCD format, each invalid nibble of the RTC registers continue counting to 0xF before rolling over to 0x0 after which RTC resumes normal operation.

Note After 'W' bit is set to '0', values written into the timekeeping, alarm, calibration, and interrupt registers are transferred to the RTC time keeping counters in t_{RTCp} time. These counter values must be saved to nonvolatile memory either by initiating a Software/Hardware STORE or AutoStore operation. While working in AutoStore disabled mode, perform a STORE operation after t_{RTCp} time while writing into the RTC registers for the modifications to be correctly recorded.

Backup Power

The RTC in the CY14B101KA is intended for permanently powered operation. The V_{RTCcap} or V_{RTCbat} pin is connected depending on whether a capacitor or battery is chosen for the application. When the primary power, V_{CC}, fails and drops below V_{SWITCH} the device switches to the backup power supply.

The clock oscillator uses very little current, which maximizes the backup time available from the backup source. Regardless of the clock operation with the primary source removed, the data stored in the nvSRAM is secure, having been stored in the nonvolatile elements when power was lost.

During backup operation, the CY14B101KA consumes $0.35 \ \mu A$ (Typical) at room temperature. The user must choose capacitor or battery values according to the application.

Backup time values based on maximum current specifications are shown in the following table. Nominal backup times are approximately two times longer.

Table 2. RTC Backup Time

Capacitor Value	Backup Time
0.1 F	72 hours
0.47 F	14 days
1.0 F	30 days

Using a capacitor has the obvious advantage of recharging the backup source each time the system is powered up. If a battery is used, a 3 V lithium is recommended and the CY14B101KA sources current only from the battery when the primary power is removed. However, the battery is not recharged at any time by the CY14B101KA. The battery capacity must be chosen for total anticipated cumulative down time required over the life of the system.



Stopping and Starting the Oscillator

The OSCEN bit in the calibration register at 0x1FFF8 controls the enable and disable of the oscillator. This bit is nonvolatile and is shipped to customers in the "enabled" (set to 0) state. To preserve the battery life when the system is in storage, OSCEN must be set to '1'. This turns off the oscillator circuit, extending the battery life. If the OSCEN bit goes from disabled to enabled, it takes approximately one second (two seconds maximum) for the oscillator to start.

While system power is off, if the voltage on the backup supply (V_{RTCcap} or V_{RTCbat}) falls below their respective minimum level, the oscillator may fail. The CY14B101KA has the ability to detect oscillator failure when system power is restored. This is recorded in the oscillator fail bit (OSCF) of the flags register at the address 0x1FFF0. When the device is powered on (V_{CC} goes above V_{SWITCH}) the OSCEN bit is checked for "enabled" status. If the OSCEN bit is enabled and the oscillator is not active within the first 5 ms, the OSCF bit is set to '1'. The system must check for this condition and then write '0' to clear the flag. Note that in addition to setting the OSCF flag bit, the time registers are reset to the "Base Time" (see Setting the Clock on page 8), which is the value last written to the timekeeping registers. The control or calibration registers and the OSCEN bit are not affected by the 'oscillator failed' condition.

Reset the value of OSCF to '0' when the time registers are written for the first time. This initializes the state of this bit which may have become set when the system was first powered on.

To reset OSCF, set the write bit 'W' (in the flags register at 0x1FFF0) to a '1' to enable writes to the Flag register. Write a '0' to the OSCF bit and then reset the write bit to '0' to disable writes.

Calibrating the Clock

The RTC is driven by a quartz controlled crystal with a nominal frequency of 32.768 kHz. Clock accuracy depends on the quality of the crystal and calibration. The crystals available in market typically have an error of \pm 20 ppm to \pm 35 ppm. However, CY14B101KA employs a calibration circuit that improves the accuracy to \pm 1/–2 ppm at 25 °C. This implies an error of \pm 2.5 seconds to –5 seconds per month.

The calibration circuit adds or subtracts counts from the oscillator divider circuit to achieve this accuracy. The number of pulses that are suppressed (subtracted, negative calibration) or split (added, positive calibration) depends upon the value loaded into the five calibration bits found in calibration register at 0x1FFF8. The calibration bits occupy the five lower order bits in the calibration register. These bits are set to represent any value between '0' and 31 in binary form. Bit D5 is a sign bit, where a '1' indicates positive calibration and a '0' indicates negative calibration. Adding counts speeds the clock up and subtracting counts slows the clock down. If a binary '1' is loaded into the register, it corresponds to an adjustment of 4.068 or -2.034 ppm offset in oscillator error, depending on the sign.

Calibration occurs within a 64-minute cycle. The first 62 minutes in the cycle may, once per minute, have one second shortened by 128 or lengthened by 256 oscillator cycles. If a binary '1' is loaded into the register, only the first two minutes of the 64-minute cycle are modified. If a binary 6 is loaded, the first 12 are affected, and so on. Therefore, each calibration step has the effect of adding 512 or subtracting 256 oscillator cycles for every 125,829,120 actual oscillator cycles, that is, 4.068 or -2.034 ppm of adjustment per calibration step in the calibration register.

To determine the required calibration, the CAL bit in the flags register (0x1FFF0) must be set to '1'. This causes the INT pin to toggle at a nominal frequency of 512 Hz. Any deviation measured from the 512 Hz indicates the degree and direction of the required correction. For example, a reading of 512.01024 Hz indicates a +20 ppm error. Hence, a decimal value of -10 (001010b) must be loaded into the calibration register to offset this error.

Note Setting or changing the calibration register does not affect the test output frequency.

To set or clear CAL, set the write bit 'W' (in the flags register at 0x1FFF0) to '1' to enable writes to the flags register. Write a value to CAL, and then reset the write bit to '0' to disable writes.

Alarm

The alarm function compares user programmed values of alarm time and date (stored in the registers 0x1FFF1-5) with the corresponding time of day and date values. When a match occurs, the alarm internal flag (AF) is set and an interrupt is generated on INT pin if alarm interrupt enable (AIE) bit is set.

There are four alarm match fields - date, hours, minutes, and seconds. Each of these fields has a match bit that is used to determine if the field is used in the alarm match logic. Setting the match bit to '0' indicates that the corresponding field is used in the match process. Depending on the match bits, the alarm occurs as specifically as once a month or as frequently as once every minute. Selecting none of the match bits (all 1s) indicates that no match bits (all 0s) causes an exact time and date match.

There are two ways to detect an alarm event: by reading the AF flag or monitoring the INT pin. The AF flag in the flags register at 0x1FFF0 indicates that a date or time match has occurred. The AF bit is set to '1' when a match occurs. Reading the flags register clears the alarm flag bit (and all others). A hardware interrupt pin may also be used to detect an alarm event.

To set, clear or enable an alarm, set the 'W' bit (in flags register -0x1FFF0) to '1' to enable writes to alarm registers. After writing the alarm value, clear the 'W' bit back to '0' for the changes to take effect.

Note CY14B101KA requires the alarm match bit for seconds (0x1FFF2–D7) to be set to '0' for proper operation of alarm flag and Interrupt.

Watchdog Timer

The watchdog timer is a free running down counter that uses the 32 Hz clock (31.25 ms) derived from the crystal oscillator. The oscillator must be running for the watchdog to function. It begins counting down from the value loaded in the watchdog timer register.

The timer consists of a loadable register and a free running counter. On power-up, the watchdog time out value in register 0x1FFF7 is loaded into the counter load register. Counting begins on power-up and restarts from the loadable value any time the watchdog strobe (WDS) bit is set to '1'. The counter is compared to the terminal value of '0'. If the counter reaches this value, it causes an internal flag and an optional interrupt output.



You can prevent the time out interrupt by setting WDS bit to '1' prior to the counter reaching '0'. This causes the counter to reload with the watchdog time out value and to be restarted. As long as the user sets the WDS bit prior to the counter reaching the terminal value, the interrupt and WDT flag never occur.

New time out values are written by setting the watchdog write bit to '0'. When the WDW is '0', new writes to the watchdog time out value bits D5–D0 are enabled to modify the time out value. When WDW is '1', writes to bits D5-D0 are ignored. The WDW function enables a user to set the WDS bit without concern that the watchdog timer value is modified. A logical diagram of the watchdog timer is shown in Figure 3. Note that setting the watchdog time out value to '0' disables the watchdog function.

The output of the watchdog timer is the flag bit WDF that is set if the watchdog is allowed to time out. If the watchdog interrupt enable (WIE) bit in the interrupt register is set, a hardware interrupt on INT pin is also generated on watchdog timeout. The flag and the hardware interrupt are both cleared when user reads the flags registers.

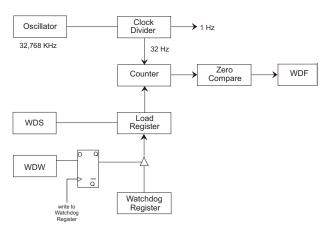


Figure 3. Watchdog Timer Block Diagram

Power Monitor

The CY14B101KA provides a power management scheme with power fail interrupt capability. It also controls the internal switch to backup power for the clock and protects the memory from low V_{CC} access. The power monitor is based on an internal band gap reference circuit that compares the V_{CC} voltage to V_{SWITCH} threshold.

As described in the AutoStore Operation on page 5, when V_{SWITCH} is reached as V_{CC} decays from power loss, a data STORE operation is initiated from SRAM to the nonvolatile elements, securing the last SRAM data state. Power is also switched from V_{CC} to the backup supply (battery or capacitor) to operate the RTC oscillator.

When operating from the backup source, read and write operations to nvSRAM are inhibited and the RTC functions are not available to the user. The RTC clock continues to operate in the background. The updated RTC time keeping registers data are available to the user after V_{CC} is restored to the device (see AutoStore/Power-Up RECALL on page 23).

Interrupts

The CY14B101KA has flags register, interrupt register and interrupt logic that can signal interrupt to the microcontroller. There are three potential sources for interrupt: watchdog timer, power monitor, and alarm timer. Each of these can be individually enabled to drive the INT pin by appropriate setting in the Interrupt register (0x1FFF6). In addition, each has an associated flag bit in the flags register (0x1FFF0) that the host processor uses to determine the cause of the interrupt. The INT pin driver has two bits that specify its behavior when an interrupt occurs.

An interrupt is raised only if both a flag is raised by one of the three sources and the respective interrupt enable bit in interrupts register is enabled (set to '1'). After an interrupt source is active, two programmable bits, H/L and P/L, determine the behavior of the output pin driver on INT pin. These two bits are located in the interrupt register and can be used to drive level or pulse mode output from the INT pin. In pulse mode, the pulse width is internally fixed at approximately 200 ms. This mode is intended to reset a host microcontroller. In the level mode, the pin goes to its active polarity until the flags register is read by the user. This mode is used as an interrupt to a host microcontroller. The control bits are summarized in the following section.

Interrupts are only generated while working on normal power and are not triggered when system is running in backup power mode.

Note CY14B101KA generates valid interrupts only after the Power-up RECALL sequence is completed. All events on INT pin must be ignored for $t_{HRECALL}$ duration after powerup.

Interrupt Register

Watchdog Interrupt Enable (WIE). When set to '1', the watchdog timer drives the INT pin and an internal flag when a watchdog time out occurs. When WIE is set to '0', the watchdog timer only affects the WDF flag in flags register.

Alarm Interrupt Enable (AIE). When set to '1', the alarm match drives the INT pin and an internal flag. When AIE is set to '0', the alarm match only affects the AF flag in flags register.

Power Fail Interrupt Enable (PFE). When set to '1', the power fail monitor drives the pin and an internal flag. When PFE is set to '0', the power fail monitor only affects the PF flag in flags register.

High/Low (H/L). When set to a '1', the INT pin is active HIGH and the driver mode is push pull. The INT pin drives HIGH only when V_{CC} is greater than V_{SWITCH} . When set to a '0', the INT pin is active LOW and the drive mode is open drain. The INT pin must be pulled up to Vcc by a 10 k resistor while using the interrupt in active LOW mode.

Pulse/Level (P/L). When set to a '1' and an interrupt occurs, the INT pin is driven for approximately 200 ms. When P/L is set to a '0', the INT pin is driven HIGH or LOW (determined by H/L) until the flags register is read.

When an enabled interrupt source activates the INT pin, an external host reads the flags registers to determine the cause. All flags are cleared when the register is read. If the INT pin is programmed for level mode, then the condition clears and the INT pin returns to its inactive state. If the pin is programmed for pulse mode, then reading the flag also clears the flag and the pin. The pulse does not complete its specified duration if the flags register is read. If the INT pin is used as a host reset, then the flags register is not read during a reset.



Flags Register

The flags register has three flag bits: WDF, AF, and PF, which can be used to generate an interrupt. These flags are set by the watchdog timeout, alarm match, or power fail monitor respectively. The processor can either poll this register or enable interrupts to be informed when a flag is set. These flags are automatically reset when the register is read. The flags register is automatically loaded with the value 0x00 on power-up (except for the OSCF bit; see Stopping and Starting the Oscillator on page 9).



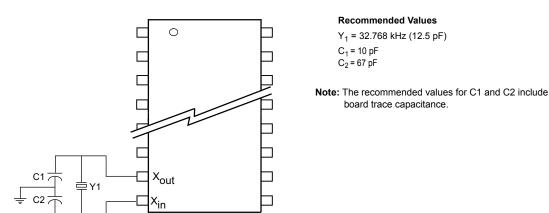


Figure 5. Interrupt Block Diagram

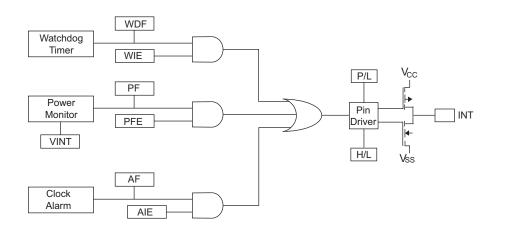






Table 3. RTC Register Map^[11, 12, 13]

Reg			F	BCD Forma	at Data ^[12]				Function/Range	
CY14B101KA	CY14B101MA	D7	D6	D5	D4	D3	D2	D1	D0	Function/Range
0x1FFFF	0x0FFFF		10s	years			Ye	ears		Years: 00–99
0x1FFFE	0x0FFFE	0	0	0	10s months		Мс	onths		Months: 01–12
0x1FFFD	0x0FFFD	0	0	10s da	ay of month		Day c	of month		Day of month: 01–31
0x1FFFC	0x0FFFC	0	0	0	0	0	I	Day of w	veek	Day of week: 01–07
0x1FFFB	0x0FFFB	0	0	10	s hours		H	ours		Hours: 00–23
0x1FFFA	0x0FFFA	0		10s min	utes		Mir	nutes		Minutes: 00–59
0x1FFF9	0x0FFF9	0	1	l0s sec	onds	Seconds Seconds: 00–59				Seconds: 00–59
0x1FFF8	0x0FFF8	OSCEN (0)	0	Cal sign (0)	Calibration (00000) Calibration value			Calibration values ^[14]		
0x1FFF7	0x0FFF7	WDS (0)	WDW (0)		WDT (000000) W				Watchdog ^[14]	
0x1FFF6	0x0FFF6	WIE (0)	AIE (0)	PFE (0)	0	H/L (1) P/L 0 0 Inter		Interrupts ^[14]		
0x1FFF5	0x0FFF5	M (1)	0	10s a	alarm date		Alarm day Alarm, day of 01–31		Alarm, day of month: 01–31	
0x1FFF4	0x0FFF4	M (1)	0	10s a	larm hours	Alarm hours Alarm, hours:		Alarm, hours: 00–23		
0x1FFF3	0x0FFF3	M (1)	10	alarm n	ninutes Alarm minutes Alarm, minu		Alarm, minutes: 00–59			
0x1FFF2	0x0FFF2	M (1)	10	alarm s	arm seconds Alarm, seconds Alarm, second			Alarm, seconds: 00–59		
0x1FFF1	0x0FFF1		10s ce	enturies			Cer	nturies		Centuries: 00–99
0x1FFF0	0x0FFF0	WDF	AF	PF	OSCF ^[15]	0	CAL (0)	W (0)	R (0)	Flags ^[14]

- Notes
 11. Upper byte D15–D8 (CY14B101MA) of RTC registers are reserved for future use.
 12. The unused bits of RTC registers are reserved for future use and should be set to '0'.
 13. () designates values shipped from the factory.
 14. This is a binary value, not a BCD value.
 15. When user resets OSCF flag bit, the flags register will be updated after t_{RTCp} time.



Table 4. Register Map Detail

Reg	ister				Deer	intion			
CY14B101KA	CY14B101MA				Descr	iption			
0.45555	0.005555								
0x1FFFF	0x0FFFF	D7	D6	D5	D4	D3	D2	D1	D0
			10s	s years			Ye	ears	
		upper nibb	ne lower two le (four bits) he register i	contains the	f the year. Lov value for 10s	wer nibble (fe of years. E	our bits) con ach nibble c	tains the val perates fror	ue for years n 0 to 9. Th
		Tange for t		30-33.	Time Keepir	na - Months	•		
0x1FFFE	0x0FFFE	D7	D6	D5	D4	D3	D2	D1	D0
		0	0	0	10s month	03		onths	00
		÷	•	-		(fa			
		from 0 to 9		ble (one bit)	n. Lower nibbl contains the u				
0	0-05555				Time Keep	ing - Date			
0x1FFFD	0x0FFFD	D7	D6	D5	D4	D3	D2	D1	D0
		0	0	10s day	of month		Day o	f month	
		and operat	tes from 0 to	o 9; upper nib	e of the month ble (two bits) Leap years a	contains the	e 10s digit a	nd operates	
		-			Time Keep	oing - Day			
0x1FFFC	0x0FFFC	D7	D6	D5	 D4	D3	D2	D1	D0
		0	0	0	0	0		Day of wee	k
		a ring cour	nter that cou	nts from 1 to	value that co 7 then return rated with the	s to 1. The u			
0x1FFFB	0x0FFFB				Time Keepi	ng - Hours		_	_
UXIIII B	UXUITI B	D7	D6	D5	D4	D3	D2	D1	D0
	•	0	0	10s	hours		H	ours	
		digit and o	perates fron		n 24 hour for er nibble (two 0–23.				
0x1FFFA	0x0FFFA				Time Keepir	ng - Minutes	6		
WIFFFA	UXUFFFA	D7	D6	D5	D4	D3	D2	D1	D0
	•	0		10s minutes	3		Mir	nutes	
		from 0 to 9	; upper nibl		Lower nibble) contains th				
	0-05550				Time Keepin	g - Second	s		
0x1FFF9	0x0FFF9	D7	D6	D5	D4	D3	D2	D1	D0
	1	0		10s second	S	1	Sec	conds	
		from 0 to 9		le (three bits	. Lower nibble) contains the				



Table 4. Register Map Detail (continued)

Reg	ister				Decer	intion				
CY14B101KA	CY14B101MA									
0x1FFF8	0x0FFF8	Calibration/Control								
•		D7	D6	D5	D4	D3	D2	D1	D0	
		OSCEN	0	Calibration sign			Calibration			
OSC	CEN			en set to '1', f r saves batter					cillator runs	
Calibrat	ion Sign	Determine from the ti		oration adjust	ment is appli	ed as an ac	dition (1) to	o or as a su	btraction (0	
Calib	ration	These five	bits control	the calibratio	n of the clocl	۲.				
0x1FFF7	0x0FFF7				WatchDo	og Timer				
		D7	D6	D5	D4	D3	D2	D1	D0	
	•	WDS	WDW			WE	DT			
WI	DS	'0' has no	effect. The b	ing this bit to bit is cleared a it always retu	automatically					
WE	W	(D5–D0). T Setting this	⁻ his allows t s bit to '0' all	e. Setting this he user to set ows bits D5– s function is e	the watchdo D0 to be writt	g strobe bit viten to the wa	without distu atchdog regi	urbing the til ster when t	meout value he next writ	
W	DT	Watchdog timeout selection. The watchdog timer inter register. It represents a multiplier of the 32 Hz count (3 31.25 ms (a setting of 1) to 2 seconds (setting of 3 Fh) disables the timer. These bits can be written only if the V				ount (31.25 f 3 Fh). Sett	ms). The ra	ange of time hdog timer	eout value register to	
0x1FFF6	0x0FFF6				nterrupt Sta	tus/Contro	I			
UXIFFFO	UXUFFF0	D7	D6	D5	D4	D3	D2	D1	D0	
		WIE	AIE	PFE	0	H/L	P/L	0	0	
WIE		Watchdog interrupt enable. When set to '1' and a watchdog timeout occurs, the watchdog time drives the INT pin and the WDF flag. When set to '0', the watchdog timeout affects only the WDF flag.								
A	IE	Alarm interrupt enable. When set to '1', the alarm match drives the INT pin and the AF flag. When set to '0', the alarm match only affects the AF flag.								
PFE		Power fail enable. When set to '1', the power fail monitor drives the INT pin and the PF flag. When set to '0', the power fail monitor affects only the PF flag.								
()	Reserved for future use								
Н	/L	High/Low. drain, activ		oʻ1', the INT p	in is driven a	ictive HIGH.	When set to	oʻ0', the IN	T pin is ope	
P	/L	for approx	el. When set mately 200 ags register	to '1', the INT ms. When se is read.	t to '0', the IN	IT pin is driv	mined by H/ ven to an act	L) by an inte tive level (a	errupt sourc s set by H/I	
0x1FFF5	0x0FFF5				Alarm	- Day				
		D7	D6	D5	D4	D3	D2	D1	D0	
		М	0		rm date		-	n date		
		Contains tl value.	ne alarm val	ue for the dat	e of the mont	h and the m	ask bit to se	lect or dese	lect the da	
Μ				s set to '0', the uit to ignore t			e alarm mat	tch. Setting	this bit to '	



Table 4. Register Map Detail (continued)

Reg	Register				Descri	ntion				
CY14B101KA	CY14B101MA									
0x1FFF4	0x0FFF4	Alarm - Hours								
UX II I I I		D7	D6	D5	D4	D3	D2	D1	D0	
		М	0		rm hours			n hours		
					ours and the n					
Ν	M				e hours value he hours valu	e.	ne alarm ma	tch. Setting	this bit to '	
0x1FFF3	0x0FFF3			_	Alarm - I					
		D7	D6	D5	D4	D3	D2	D1	D0	
		M		s alarm minu			-	minutes		
					nutes and the					
Ν	M				e minutes val re the minutes		n the alarm	match. Setti	ng this bit t	
0x1FFF2	0x0FFF2				Alarm - S	econds	-			
0,11112	0,01112	D7	D6	D5	D4	D3	D2	D1	D0	
		М	10	s alarm seco	onds		Alarm	seconds		
		Contains t	he alarm valı	ue for the sec	onds and the i	mask bit to s	electordes	elect the sec	onds' valu	
Ν	M	Match. When this bit is set to '0', the seconds value is used in the alarm match. '1' causes the match circuit to ignore the seconds value.						match. Setti	ng this bit	
0x1FFF1	0x0FFF1	Time Keeping - Centuries								
•		D7	D6	D5	D4	D3	D2	D1	D0	
				enturies				ituries		
		Contains t to 9; upper 0–99 cent	r nibble cont	ie of centurie ains the uppe	es. Lower nibb er digit and op	ble contains perates from	the lower d 0 to 9. The	igit and oper range for th	rates from le register	
0~45550	0×05550				Flag	gs				
0x1FFF0	0x0FFF0	D7	D6	D5	D4	D3	D2	D1	D0	
		WDF	AF	PF	OSCF	0	CAL	W	R	
W	DF				bit is set to ' is cleared to (
А	١F				to '1' when th 0. It is cleare					
Р	PF				is set to '1' w e flags registe				ail thresho	
OS	SCF	Oscillator fail flag. Set to '1' on power-up if the oscillator is enabled a 5 ms of operation. This indicates that RTC backup power failed and clo This bit survives the power cycle and is never cleared internally by the for this condition and write '0' to clear this flag. When user resets OS updated after t _{RTCp} time.					ed and clock Illy by the ch	value is no l nip. The user	longer valie must chec	
C	AL				a 512 Hz squ eration. This t					
V	W Write enable: Setting the 'W' bit to '1' freezes updates of the RTC registers. The u write to RTC registers, alarm registers, calibration register, interrupt register and t Setting the 'W' bit to '0' causes the contents of the RTC registers to be transferred keeping counters if the time has changed. This transfer process takes t _{RTCp} time This bit defaults to 0 on power-up.						gister and fla transferred	ags registe I to the tim		
F	2	Read enat	ble: Setting 'I en during the	R' bit to '1', sto e reading pro	ops clock upd ocess. Set 'R' quire 'W' bit to	bit to '0' to r	esume cloc	k updates to	the holdin	



Best Practices

nvSRAM products have been used effectively for over 27 years. While ease-of-use is one of the product's main system values, experience gained working with hundreds of applications has resulted in the following suggestions as best practices:

- The nonvolatile cells in this nvSRAM product are delivered from Cypress with 0x00 written in all cells. Incoming inspection routines at customer or contract manufacturer's sites sometimes reprogram these values. Final NV patterns are typically repeating patterns of AA, 55, 00, FF, A5, or 5A. End product's firmware should not assume an NV array is in a set programmed state. Routines that check memory content values to determine first time system configuration, cold or warm boot status, and so on should always program a unique NV pattern (that is, complex 4-byte pattern of 46 E6 49 53 hex or more random bytes) as part of the final system manufacturing test to ensure these system routines work consistently.
- Power-up boot firmware routines should rewrite the nvSRAM into the desired state (for example, AutoStore enabled). While the nvSRAM is shipped in a preset state, best practice is to again rewrite the nvSRAM into the desired state as a safeguard against events that might flip the bit inadvertently such as program bugs and incoming inspection routines.
- The V_{CAP} value specified in this data sheet includes a minimum and a maximum value size. Best practice is to meet this requirement and not exceed the maximum V_{CAP} value because the nvSRAM internal algorithm calculates V_{CAP} charge and discharge time based on this maximum V_{CAP} value. Customers that want to use a larger V_{CAP} value to make sure there is extra store charge and store time should discuss their V_{CAP} size selection with Cypress to understand any impact on the V_{CAP} voltage level at the end of a t_{RECALL} period.
- When base time is updated, these updates are transferred to the time keeping registers when 'W' bit is set to '0'. This transfer takes t_{RTCp} time to complete. It is recommended to initiate software STORE or Hardware STORE after t_{RTCp} time to save the base time into nonvolatile memory.



Maximum Ratings

Exceeding maximum ratings may impair the useful life of the device. These user guidelines are not tested.

Storage temperature65 °C to +150 °C
Maximum accumulated storage time
At 150 °C ambient temperature 1000 h
At 85 °C ambient temperature 20 Years
Ambient temperature with power applied
Supply voltage on V_{CC} relative to V_{SS} –0.5 V to 4.1 V
Voltage applied to outputs in High Z state0.5 V to V _{CC} + 0.5 V Input voltage0.5 V to V _{CC} + 0.5 V

Transient voltage (< 20 ns) on any pin to ground potential–2.0 V to V_{CC} + 2.0 V
Package power dissipation capability (T _A = 25 °C) 1.0 W
Surface mount Pb soldering temperature (3 seconds)+260 °C
DC output current (1 output at a time, 1s duration) 15 mA
Static discharge voltage (per MIL-STD-883, Method 3015) > 2001 V
Latch up current > 200 mA

Operating Range

Range	Ambient Temperature	V _{cc}
Industrial	–40 °C to +85 °C	2.7 V to 3.6 V

DC Electrical Characteristics

Parameter	Description	Test Conditions	Min	Typ ^[16]	Max	Unit
V _{CC}	Power supply voltage		2.7	3.0	3.6	V
I _{CC1}	Average V _{cc} current	t_{RC} = 25 ns t_{RC} = 45 ns Values obtained without output loads (I_{OUT} = 0 mA)	-	_	70 52	mA mA
I _{CC2}	Average V _{CC} current during STORE	All inputs don't care, V _{CC} = Max. Average current for duration t _{STORE}	-	-	10	mA
I _{CC3} ^[16]	Average V _{CC} current at t _{RC} = 200 ns, V _{CC(Typ)} , 25 °C	All inputs cycling at CMOS levels. Values obtained without output loads (I _{OUT} = 0 mA).	_	35	-	mA
I _{CC4}	Average V _{CAP} current during AutoStore cycle	All inputs don't care. Average current for duration t _{STORE}	-	-	5	mA
I _{SB}	V _{CC} standby current	$\label{eq:cell} \begin{array}{l} \hline CE \geq (V_{CC}-0.2 \ V). \\ V_{IN} \leq 0.2 \ V \ or \geq (V_{CC}-0.2 \ V). \ W \ \text{bit set to '0'}. \\ \hline Standby \ current \ level \ after \ nonvolatile \ cycle \\ is \ complete. \ Inputs \ are \ static. \ f = 0 \ MHz. \end{array}$	-	_	5	mA
I _{IX} ^[17]	Input leakage current (except HSB)	V_{CC} = Max, $V_{SS} \le V_{IN} \le V_{CC}$	-1	-	+1	μA
	Input leakage current (for HSB)	V_{CC} = Max, $V_{SS} \le V_{IN} \le V_{CC}$	-100	_	+1	μA
I _{OZ}	Off state output leakage current	$\frac{V_{CC}}{CE \text{ or } OE \geq V_{IH} \text{ or } BHE/BLE \geq V_{IH} \text{ or } WE \leq V_{IL}$	-1	-	+1	μA
V _{IH}	Input HIGH voltage		2.0	-	V _{CC} + 0.5	V
V _{IL}	Input LOW voltage		$V_{SS} - 0.5$	-	0.8	V
V _{OH}	Output HIGH voltage	I _{OUT} = –2 mA	2.4	-	-	V
V _{OL}	Output LOW voltage	I _{OUT} = 4 mA	-	-	0.4	V
V _{CAP} ^[18]	Storage capacitor	Between V_{CAP} pin and V_{SS} , 5 V rated	61	68	180	μF

Over the Operating Range (V_{CC} = 2.7 V to 3.6 V)

Notes

16. Typical values are at 25 °C, $V_{CC} = V_{CC(Typ)}$. Not 100% tested. 17. The HSB pin has $I_{OUT} = -2 \mu A$ for V_{OH} of 2.4 V when both active HIGH and low drivers are disabled. When they are enabled standard V_{OH} and V_{OL} are valid. This parameter is characterized but not tested.

B. Min V_{CAP} value guarantees that there is a sufficient charge available to complete a successful AutoStore operation. Max V_{CAP} value guarantees that the capacitor on V_{CAP} is charged to a minimum voltage during a Power-Up RECALL cycle so that an immediate power-down cycle can complete a successful AutoStore. Therefore it is always recommended to use a capacitor within the specified min and max limits. Refer application note AN43593 for more details on V_{CAP} options.



Data Retention and Endurance

Over the Operating Range

Parameter	Description	Min	Unit
DATA _R	Data retention	20	Years
NV _C	Nonvolatile STORE operations	1,000	К

Capacitance

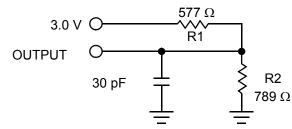
Parameter ^[19]	Description	Test Conditions	Max	Unit
C _{IN}	Input capacitance (except BHE, BLE and HSB)	$T_A = 25 \text{ °C}, f = 1 \text{ MHz}, V_{CC} = V_{CC(Typ)}$	7	pF
	Input capacitance (for BHE, BLE and HSB)		8	pF
C _{OUT}	Output capacitance (except HSB)		7	pF
	Output capacitance (for HSB)		8	pF

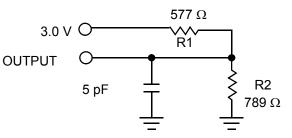
Thermal Resistance

Parameter ^[19] Description		Test Conditions	48-pin SSOP	44-pin TSOP II	54-pin TSOP II	Unit
Θ_{JA}	Thermal resistance (Junction to ambient)	Test conditions follow standard test methods and procedures for measuring	37.47	41.74	36.4	°C/W
Θ_{JC}	Thermal resistance (Junction to case)	thermal impedance, in accordance with EIA/JESD51.	24.71	11.90	10.13	°C/W

AC Test Loads

Figure 6. AC Test Loads





AC Test Conditions

Input pulse levels	0 V to 3 V
Input rise and fall times (10%–90%)	<u><</u> 3 ns
Input and output timing reference levels	1.5 V

Note 19. These parameters are guaranteed by design and are not tested.



RTC Characteristics

Over the Operating Range

Parameter	Description			Тур ^[20]	Max	Units
V _{RTCbat}	RTC battery pin voltage		1.8	3.0	3.6	V
I _{BAK} ^[21]	RTC backup current	T _A (Min)	-	-	0.35	μA
		25 °C	-	0.35	-	μA
		T _A (Max)	-	-	0.5	μA
V _{RTCcap} ^[22]	RTC capacitor pin voltage	T _A (Min)	1.6	-	3.6	V
		25 °C	1.5	3.0	3.6	V
		T _A (Max)	1.4	-	3.6	V
tOCS	RTC oscillator time to start		-	1	2	sec
t _{RTCp}	RTC processing time from end of 'W' bit set to '0'		-	-	350	μS
R _{BKCHG}	RTC backup capacitor charge current-limiting resistor		350	_	850	Ω

Notes

 ^{20.} These parameters are guaranteed by design and are not tested.
 21. From either V_{RTCcap} or V_{RTCbat}.
 22. If V_{RTCcap} > 0.5 V or if no capacitor is connected to V_{RTCcap} pin, the oscillator starts in t_{OCS} time. If a backup capacitor is connected and V_{RTCcap} < 0.5 V, the capacitor must be allowed to charge to 0.5 V for oscillator to start.

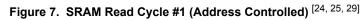


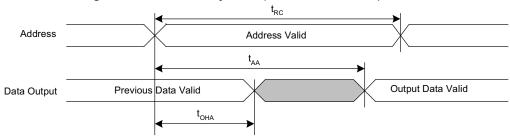
AC Switching Characteristics

Over the Operating Range

Parame	eters ^[23]		25	ins	45	ns	
Cypress Parameter Alt Parameter		Description	Min Max		Min	Мах	Unit
SRAM Read Cy	cle						
t _{ACE}	t _{ACS}	Chip enable access time	-	25	-	45	ns
t _{RC} ^[24]	t _{RC}	Read cycle time	25	-	45	-	ns
t _{AA} ^[25]	t _{AA}	Address access time	-	25	-	45	ns
t _{DOF}	t _{OE}	Output enable to data valid	-	12	-	20	ns
t _{OHA} [25]	t _{OH}	Output hold after address change	3	-	3	-	ns
t _{LZCE} ^[26, 27]	t _{LZ}	Chip enable to output active	3	-	3	-	ns
tuzce ^[26, 27]	t _{HZ}	Chip disable to output inactive	-	10	-	15	ns
t ₁₇₀ [26, 27]	t _{OLZ}	Output enable to output active	0	-	0	-	ns
t _{HZOF} ^[26, 27]	t _{OHZ}	Output disable to output inactive	-	10	-	15	ns
t _{PU} ^[26]	t _{PA}	Chip enable to power active	0	-	0	-	ns
t _{PD} ^[26]	t _{PS}	Chip disable to power standby	-	25	-	45	ns
t _{DBE}	-	Byte enable to data valid	-	12	_	20	ns
t _{LZBE} ^[26]	-	Byte enable to output active	0	-	0	-	ns
t _{HZBE} ^[26]	-	Byte disable to output inactive	-	10	-	15	ns
SRAM Write Cy	cle	•		•	•	•	
t _{WC}	t _{WC}	Write cycle time	25	-	45	-	ns
t _{PWE}	t _{WP}	Write pulse width	20	-	30	-	ns
t _{SCE}	t _{CW}	Chip enable to end of write	20	-	30	-	ns
t _{SD}	t _{DW}	Data setup to end of write	10	-	15	-	ns
t _{HD}	t _{DH}	Data hold after end of write	0	-	0	-	ns
t _{AW}	t _{AW}	Address setup to end of write	20	-	30	-	ns
t _{SA}	t _{AS}	Address setup to start of write	0	-	0	-	ns
t _{HA}	t _{WR}	Address hold after end of write	0	_	0	-	ns
t _{HZWE} [26, 27, 28]	t _{WZ}	Write enable to output disable	-	10	-	15	ns
t _{LZWE} ^[26, 27]	t _{OW}	Output active after end of write	3	-	3	-	ns
t _{BW}	-	Byte enable to end of write	20	-	30	-	ns

Switching Waveforms





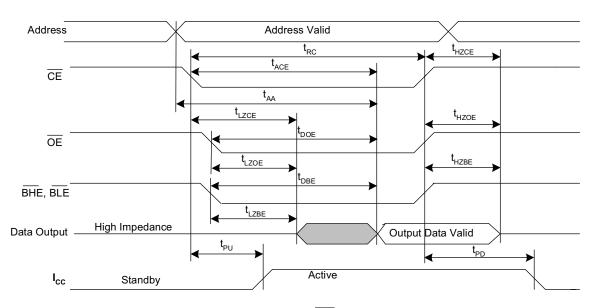
Notes

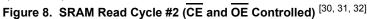
- 23. Test conditions assume signal transition time of 3 ns or less, timing reference levels of V_{CC}/2, input pulse levels of 0 to V_{CC(typ)}, and output loading of the specified log/log and load capacitance shown in Figure 6 on page 18.
 24. WE must be HIGH during SRAM read cycles.
 25. Device is continuously selected with CE, OE, and BHE/BLE LOW.

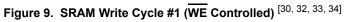
- 26. These parameters are guaranteed by design and are not tested.
- 27. Measured ±200 mV from steady state output voltage.
- If WE is low when CE goes low, the outputs remain in the high impedance state.
 HSB must remain HIGH during Read and Write cycles.

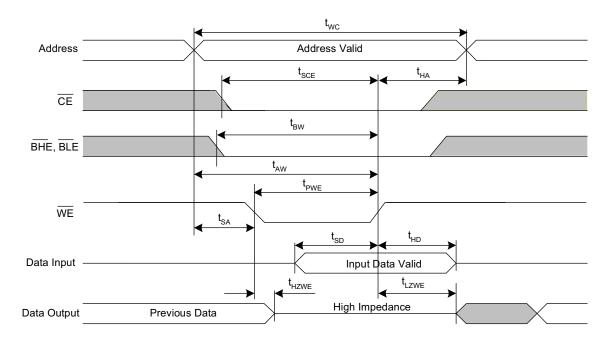


Switching Waveforms (continued)









Note

- <u>BHE</u> and <u>BLE</u> are applicable for × 16 configuration only.
 <u>WE</u> must be HIGH during SRAM read cycles.
- 32. HSB must remain HIGH during read and write cycles.
- 33. If \overline{WE} is LOW when \overline{CE} goes LOW, the outputs remain in the high impedance state. 34. \overline{CE} or \overline{WE} must be $\geq V_{IH}$ during address transitions.



Switching Waveforms (continued)

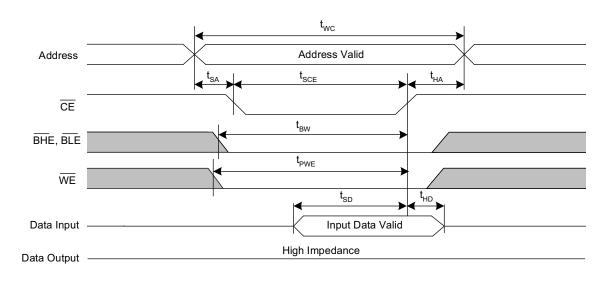
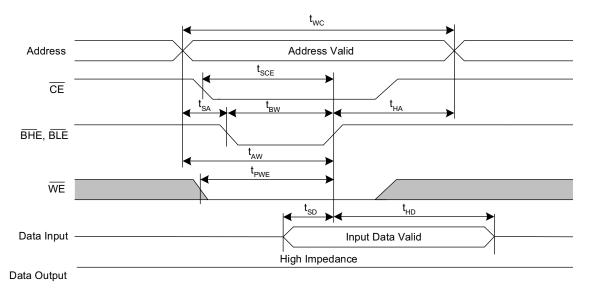


Figure 10. SRAM Write Cycle #2 (CE Controlled) ^[35, 36, 37, 38]

Figure 11. SRAM Write Cycle #3 (BHE and BLE Controlled) ^[36, 37, 38, 39, 40]

(Not applicable for RTC register writes)



Note

- 35. BHE and BLE are applicable for × 16 configuration only.
 36. If WE is LOW when CE goes LOW, the outputs remain in the high impedance state.
 37. HSB must remain HIGH during read and write cycles.

- 38. CE or WE must be \geq V_H during address transitions. 39. While there are 19 address lines on the CY14B101KA (18 address lines on the CY14B101MA), only 13 address lines (A₁₄–A₂) are used to control software modes. The remaining address lines are don't care. 40. Only CE and WE controlled writes to RTC registers are allowed. BLE pin must be held LOW before CE or WE pin goes LOW for writes to RTC register.



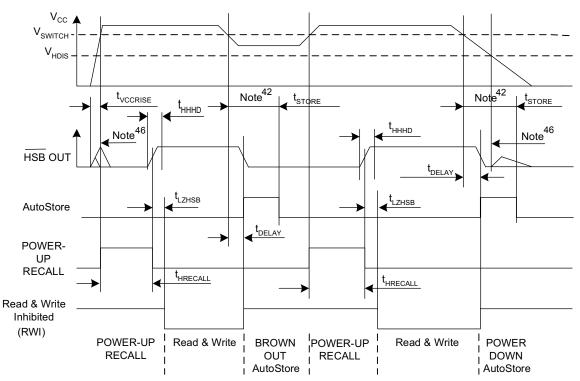
AutoStore/Power-Up RECALL

Over the Operating Range

Parameter	Description	CY14B101KA	Unit	
Farameter	Description	Min	Мах	Unit
t _{HRECALL} ^[41]	Power-Up RECALL duration	_	20	ms
t _{STORE} ^[42]			8	ms
t _{DELAY} ^[43]	Time allowed to complete SRAM write cycle	_	25	ns
V _{SWITCH}	Low voltage trigger level	_	2.65	V
t _{VCCRISE} [44]	V _{CC} rise time	150	_	μs
V _{HDIS} ^[44]	HSB output disable voltage	-	1.9	V
t _{LZHSB} ^[44]	HSB to output active time	-	5	μs
t _{HHHD} ^[44]	HSB high active time	_	500	ns

Switching Waveforms

Figure 12. AutoStore or Power-Up RECALL ^[45]



Notes

- 41. t_{HRECALL} starts from the time V_{CC} rises above V_{SWITCH}.
 42. If an SRAM write has not taken place since the last nonvolatile cycle, no AutoStore or Hardware STORE takes place
 43. On a Hardware STORE and AutoStore initiation, SRAM write operation continues to be enabled for time t_{DELAY}.
- 44. These parameters are guaranteed by design and are not tested.
- Hand Write cycles are ignored during STORE, RECALL, and while V_{CC} is below V_{SWITCH}.
 During power-up and power-down, HSB glitches when HSB pin is pulled up through an external resistor.

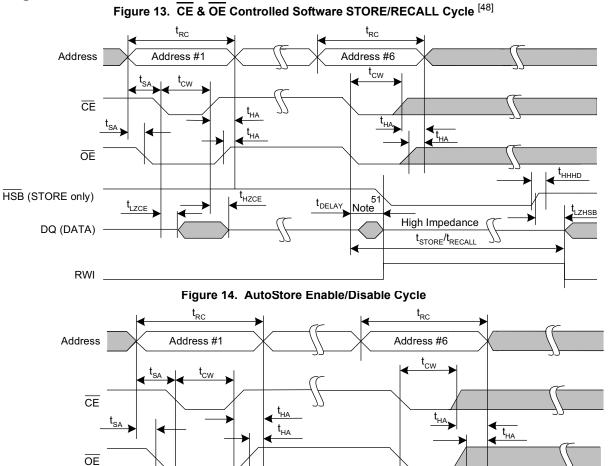


Software Controlled STORE/RECALL Cycle

Over the Operating Range

Parameter ^[47, 48]	Description	25 ns		45 ns		Unit
Falameter	Description	Min	Max	Min	Max	Onit
t _{RC}	STORE/RECALL initiation cycle time	25	-	45	_	ns
t _{SA}	Address setup time	0	-	0	-	ns
t _{CW}	Clock pulse width	20	-	30	-	ns
t _{HA}	Address hold time	0	_	0	_	ns
t _{RECALL}	RECALL duration	_	200	_	200	μs
t _{SS} ^[49, 50]	Soft sequence processing time	-	100	-	100	μs

Switching Waveforms



47. The software sequence is clocked with CE controlled or OE controlled reads.

DQ (DATA)

- 48. The six consecutive addresses must be read in the order listed in Table 1. WE must be HIGH during all six consecutive cycles.
- 49. This is the amount of time it takes to take action on a soft sequence command. Vcc power must remain HIGH to effectively register command. 50. Commands such as STORE and RECALL lock out I/O until operation is complete which further increases this time. See the specific command.

t_{HZCE}

- 51. DQ output data at the sixth read may be invalid since the output is disabled at t_{DELAY} time.

t_{LZCE}

t_{ss}

t_{DELAY}

51

Note



Hardware STORE Cycle

Over the Operating Range

Parameter	Description	CY14B101KA	CY14B101MA	Unit
Falameter	Description	Min Max		Onit
t _{DHSB}	HSB to output active time when write latch not set	-	25	ns
t _{PHSB}	Hardware STORE pulse width	15	_	ns

Switching Waveforms

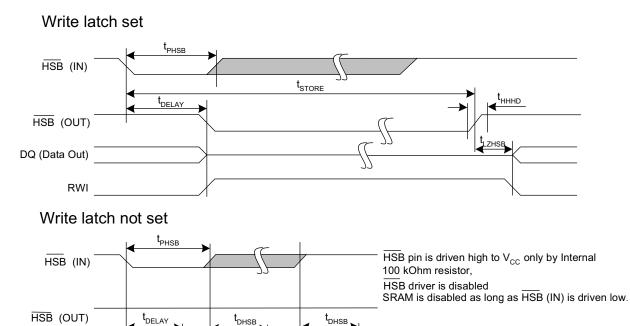
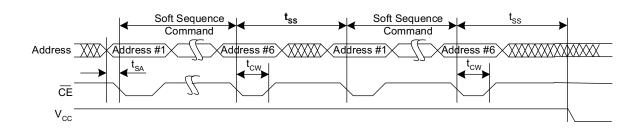


Figure 15. Hardware STORE Cycle [52]





Notes

- 52. If an SRAM write has not taken place since the last nonvolatile cycle, no AutoStore or Hardware STORE takes place.
- 53. This is the amount of time it takes to take action on a soft sequence command. V_{CC} power must remain HIGH to effectively register command. 54. Commands such as STORE and RECALL lock out I/O until operation is complete which further increases this time. See the specific command.

RWI



Truth Table For SRAM Operations

HSB must remain HIGH for SRAM operations.

Table 5. Truth Table for × 8 Configuration

CE	WE	OE	Inputs/Outputs ^[55]	Mode	Power
Н	Х	Х	High Z	Deselect/Power-down	Standby
L	Н	L	Data out (DQ ₀ –DQ ₇)	Read	Active
L	Н	Н	High Z	Output disabled	Active
L	L	Х	Data in (DQ ₀ –DQ ₇)	Write	Active

Table 6. Truth Table for × 16 Configuration

CE	WE	OE	BHE ^[56]	BLE ^[56]	Inputs/Outputs ^[55]	Mode	Power
Н	Х	Х	Х	Х	High Z	Deselect/Power-down	Standby
L	Х	Х	Н	Н	High Z	Output disabled	Active
L	Н	L	L	L	Data out (DQ ₀ –DQ ₁₅)	Read	Active
L	Н	L	Н	L	Data out (DQ ₀ –DQ ₇) DQ ₈ –DQ ₁₅ in High Z	Read	Active
L	Н	L	L	Н	Data out (DQ ₈ –DQ ₁₅) DQ ₀ –DQ ₇ in High Z	Read	Active
L	Н	Н	L	L	High Z	Output disabled	Active
L	Н	Н	Н	L	High Z	Output disabled	Active
L	Н	Н	L	Н	High Z	Output disabled	Active
L	L	Х	L	L	Data in (DQ ₀ –DQ ₁₅)	Write	Active
L	L	Х	Н	L	Data in (DQ ₀ –DQ ₇) DQ ₈ –DQ ₁₅ in High Z	Write	Active
L	L	х	L	Н	Data in (DQ ₈ –DQ ₁₅) DQ ₀ –DQ ₇ in High Z	Write	Active

Notes

55. <u>Data</u> DQ₀–DQ₇ for × 8 configuration and Data DQ₀–DQ₁₅ for × 16 configuration. 56. BHE and BLE are applicable for × 16 configuration only.



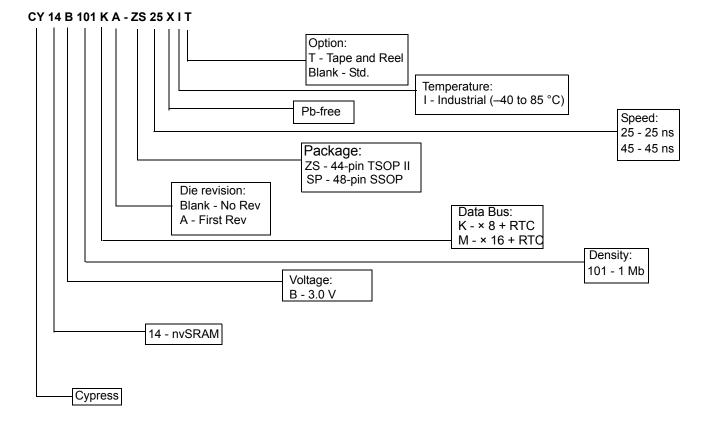
Ordering Information

Cypress offers other versions of this type of product in many different configurations and features. The below table contains only the list of parts that are currently available. For a complete listing of all options, visit the Cypress website at www.cypress.com and refer to the product summary page at http://www.cypress.com/products or contact your local sales representative. Cypress maintains a worldwide network of offices, solution centers, manufacturer's representatives and distributors. To find the office closest to you, visit us at http://www.cypress.com/go/datasheet/offices.

Speed (ns)	Ordering Code	Package Diagram	Package Type	Operating Range
25	CY14B101KA-ZS25XIT	51-85087	44-pin TSOP II	Industrial
	CY14B101KA-ZS25XI	51-85087	44-pin TSOP II	
	CY14B101KA-SP25XIT	51-85061	48-pin SSOP	
	CY14B101KA-SP25XI	51-85061	48-pin SSOP	
45	CY14B101KA-ZS45XIT	51-85087	44-pin TSOP II	
	CY14B101KA-ZS45XI	51-85087	44-pin TSOP II	
	CY14B101KA-SP45XIT	51-85061	48-pin SSOP	
	CY14B101KA-SP45XI	51-85061	48-pin SSOP	

All the above parts are Pb-free.

Ordering Code Definitions





Package Diagrams

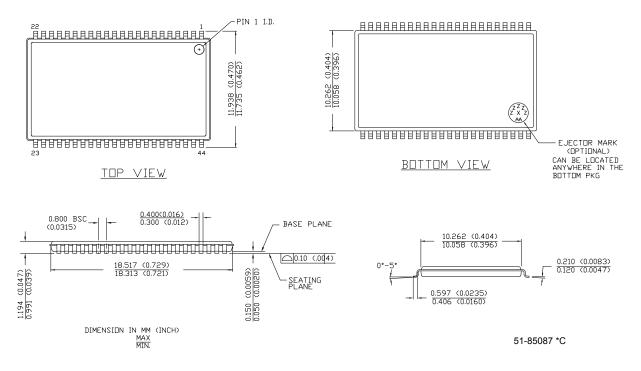
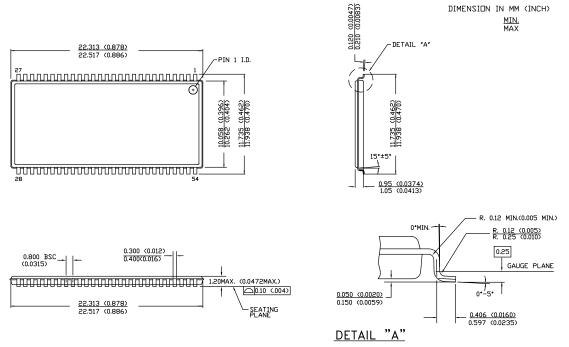


Figure 17. 44-pin TSOP II, 51-85087

Figure 18. 54-pin TSOP II (22.4 × 11.84 × 1.0 mm), 51-85160

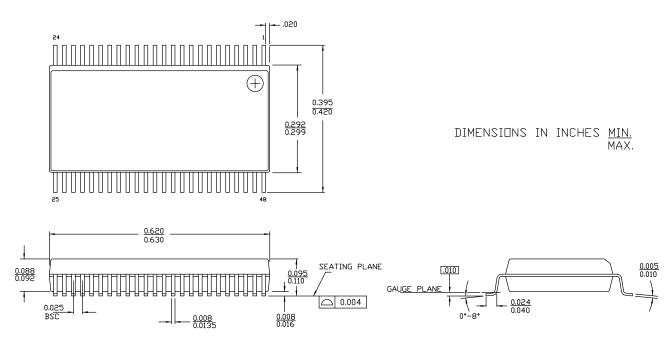


51-85160 *A



Package Diagrams (continued)





51-85061 *D



Acronyms

Acronym	Description
BCD	binary coded decimal
BHE	byte high enable
BLE	byte low enable
CE	chip enable
CMOS	complementary metal oxide semiconductor
EIA	electronic industries alliance
HSB	hardware store busy
I/O	input/output
nvSRAM	non-volatile static random access memory
OE	output enable
RoHS	restriction of hazardous substances
RWI	read and write inhibited
RTC	real time clock
SRAM	static random access memory
SSOP	shrink small outline package
TSOP	thin small outline package
WE	write enable

Document Conventions

Units of Measure

Symbol	Unit of Measure
°C	degree Celsius
F	Farads
Hz	Hertz
kbit	1024 bits
kHz	kilo Hertz
kΩ	kilo ohms
MHz	Mega Hertz
μA	micro Amperes
μF	micro Farads
μS	micro seconds
mA	milli Amperes
ms	milli seconds
ns	nano seconds
Ω	ohms
%	percent
pF	pico Farads
ppm	parts per million
V	Volts
W	Watts



Document History Page

Document Title: CY14B101KA/CY14B101MA, 1-Mbit (128 K × 8/64 K × 16) nvSRAM with Real Time Clock Document Number: 001-42880

Submission	Orig. of	Description of Change
Date	Change	Description of Change
	UNC / PYRS	New Data Sheet
11/18/2008	GVCH / AESA	Removed 15 ns access speed, updated "Features", added CY14B101MA (x16) part, changed tille to "CY14B101KA/CY14B101MA, 1-Mbit (128K x 8/64K x 16) nvSRAM with Real-Time-Clock". Added 54-pin TSOP III package related information, updated Logic block diagram, added footnote 1 and 2. Pin definition: Updated WE, HSB and NC pin description. Page 4: Updated Software store and software recall description Updated Figure 2, Page 4: Updated Hardwares tore operation and Hardware RECALL (Power up) description Footnote 1 and 10 referenced for Mode selection Table Added footnote 10, updated footnote 8 and 9 Page 6: updated Data protection description Page 7: Updated Lata protection description Page 7: Updated Saftware tock description Page 7: Updated Lata protection description Page 7: Updated Calibrating the clock description Page 7: Updated Calibrating the clock description Page 8: Added Flags register Updated Register map detail Table 5 Maximum Ratings: Added Max. Accumulated storage time Changed Output short circuit current parameter name to DC output current Changed I _{CC2} from 6 mA to 10 mA Changed I _{CC3} from 6 mA to 35 mA Changed I _{CC4} from 6 mA to 5 mA Added oftorton 10, updated footnote 16 Added dotontot 14 and 15, added footnote 16 Added dotontot 16. And 15, added footnote 16 Added dotontot 14 and 15, added footnote 16 Added tortonte 14 and 15, added footnote 16 Added thermal resistance value to 44/54 TSOP II packages Updated Input Rise and Fall time in AC test Conditions Changed V _{RTCcap} min value from 1.2 to 1.5V for industrial Commercial temperature Updated Root 22 to to _{DHA} parameter Updated Root 22 to to _{DHA} parameter Updated Root 22. added footnote 25 Added Figure 11 (SRAM WRITE CYCLE:BHE and BLE controlled) Changed t _{STORE} max value form 15ms to 8ms Updated footnote 29, added footnote 31 and 32 Software controlled STORE/RECALL Table: Changed t _{AS} to t _{SA} Changed t _{STORE} frama value from 15ms to 8ms Updated tootnote 29, added footnote 31 and 32 Software controlled STORE/RECALL Table: Changed t _{AS} to t
	Date See ECN	DateChangeSee ECNUNC / PYRS11/18/2008GVCH /



Document History Page (continued)

Document Title: CY14B101KA/CY14B101MA, 1-Mbit (128 K × 8/64 K × 16) nvSRAM with Real Time Clock Document Number: 001-42880 Submission Orig. of ECN No. **Description of Change** Rev. Date Change *B 02/05/09 2654484 GVCH / Changed the data sheet from Advance information to Preliminary PYRS Changed X₁, X₂ pin names to X_{out}, X_{in} respectively Updated Real Time Clock operation description Added footnotes 11 and 12 Added default values to RTC Register Map" table 3 Updated flag register description in Register Map Detail" table 4 Changed C1, C2 values to 21pF, 21pF respectively Changed IBAK value from 350 nA to 450 nA at hot temperature Changed V_{RTCcap} typical value from 2.4V to 3.0V Referenced Note 15 to parameters t_{LZCE}, t_{HZCE}, t_{LZOE}, t_{HZOE}, t_{LZBE}, t_{LZBE}, t_{LZWE}, t_{H7WF}and t_{H7BF} Added footnote 24 Updated Figure 13 Page 3; Added note to AutoStore Operation description *C 2733909 07/09/09 GVCH / AESA Page 4; Updated Hardware STORE (HSB) Operation description Page 4; Updated Software STORE Operation description Added best practices Changed C1, C2 values to 10pF, 67pF respectively Changed I_{BAK} and V_{RTCcap} parameter values Added R_{BKCHG} parameter Updated V_{HDIS} parameter description Updated t_{DELAY} parameter description Updated footnote 28 and added footnote 35 GVCH *D 2757375 08/28/09 Moved data sheet status from Preliminary to Final Removed commercial temperature related specs Removed 20ns access speed related specs Updated Thermal resistance values for all the packages Changed V_{RTCbat} max value from 3.3V to 3.6V Changed R_{BKCHG}^{n} min value from 450 Ω to 350 Ω Updated footnote 18 *E Changed STORE cycles to QuantumTrap from 200K to 1 Million 2767333 01/06/10 GVCH / PYRS Added Data Retention and Endurance table Updated I_{BAK} RTC backup current spec unit from nA to μA Added Contents. 03/26/10 GVCH Added more clarity on HSB pin operation *F 2899937 Table 1: Added more clarity on BHE/BLE pin opeartion Updated HSB pin operation in Switching Waveforms Updated footnote 30 Updated Ordering Information table. Updated package diagrams. Updated copyright section. *G GVCH 3134300 01/11/2011 Updated Setting the Clock description Added footnote 15 Updated 'W' bit desription in Register Map Detail table Updated best practices Updated input capacitance for BHE and BLE pin Updated input and output capacitance for HSB pin Added t_{RTCp} parameter to RTC Characteristics table Figure 12: Typo error fixed Added Acronyms table and Document Conventions table 01/21/2011 GVCH *H 3150308 No technical updates



Document History Page (continued)

Document Title: CY14B101KA/CY14B101MA, 1-Mbit (128 K × 8/64 K × 16) nvSRAM with Real Time Clock Document Number: 001-42880					
Rev.	ECN No.	Submission Date	Orig. of Change	Description of Change	
*	3313245	07/14/2011	GVCH	Updated DC Electrical Characteristics (Added Note 18 and referred the same note in V_{CAP} parameter). Updated AC Switching Characteristics (Added Note 23 and referred the same note in Parameters).	



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